

## Electronic Supplementary Information

### Improving field emission by constructing CsI-AlN hybrid nanostructures

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#### Index

SI-1. Setup for CsI evaporation

SI-2. XRD patterns, EDS spectra and SEM characterization of the samples

SI-3. (HR)TEM characterization on the CsI-AlN-8 sample

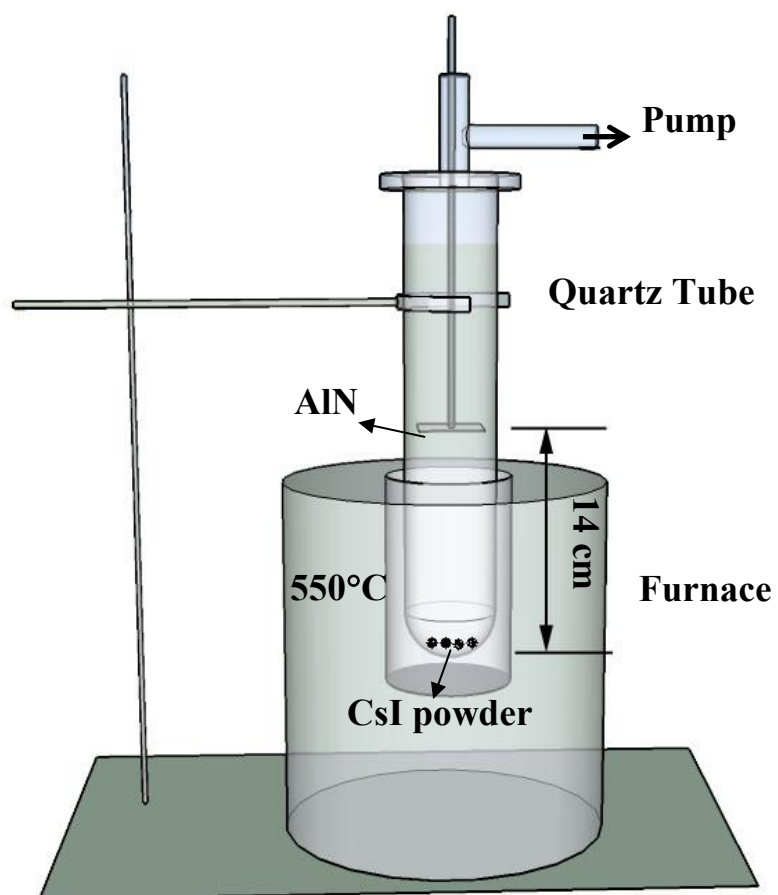
SI-4.  $E_{to}$  and  $E_{thr}$  of the patterned and unpatterned CsI-AlN-6 nanostructures

SI-5. Comparison of  $E_{to}$  and  $E_{thr}$  between CsI-AlN-6 and some other nanostructures

SI-6. XPS spectra of the hybrid samples before and after field emission measurement

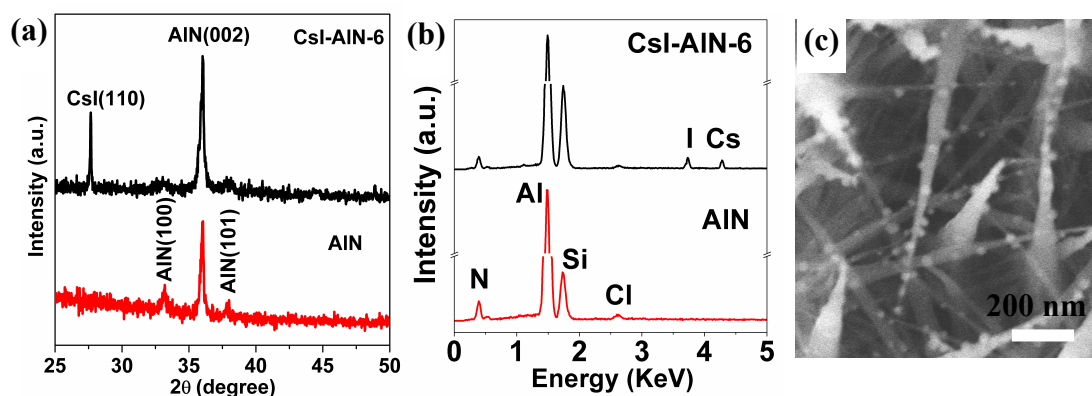
#### Reference

### SI-1. Setup for CsI evaporation



**Fig. S1** Setup for CsI evaporation.

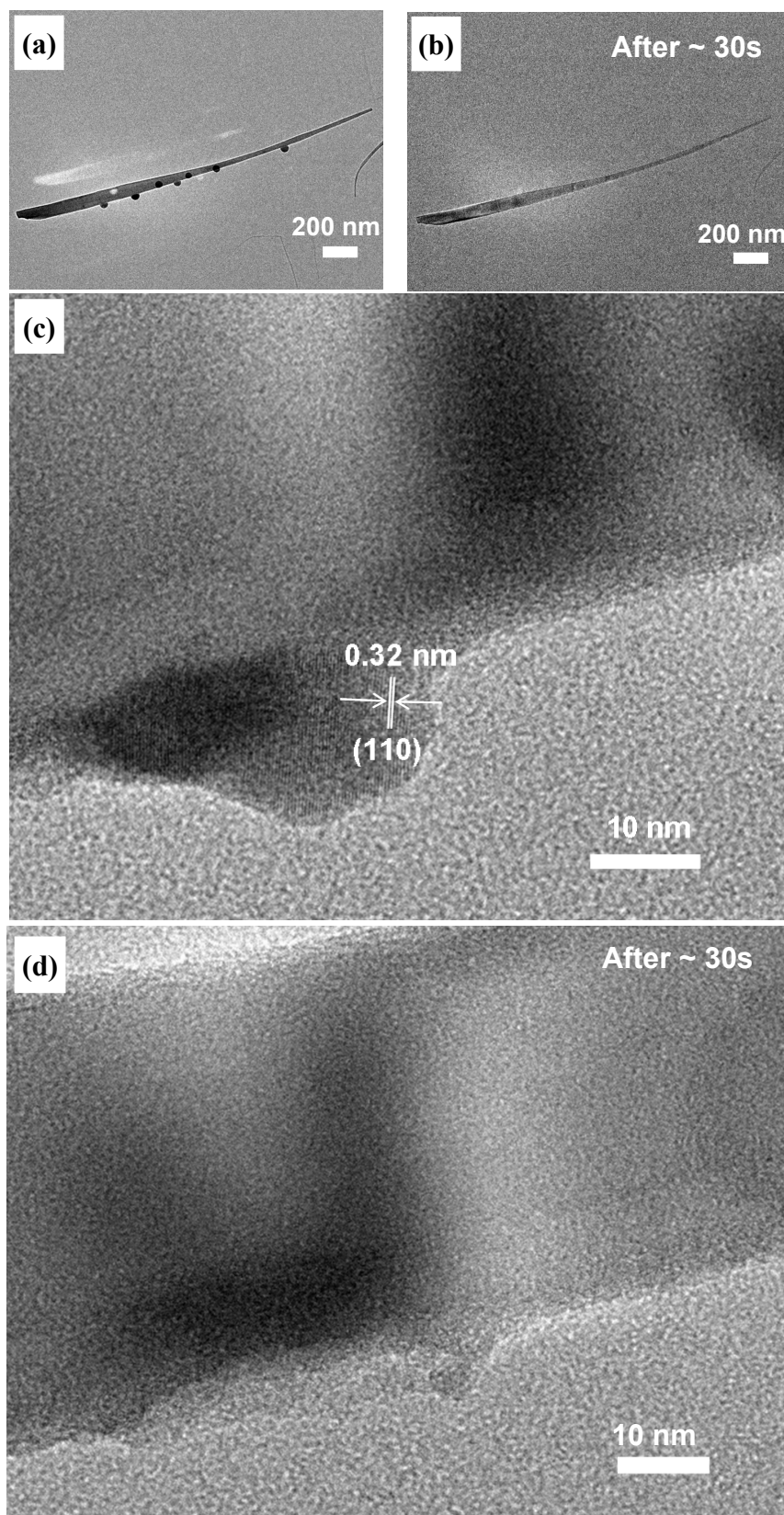
## SI-2. XRD patterns, EDS spectra and SEM characterization of the samples



**Fig. S2** XRD patterns (a) and EDS spectra (b) of the pristine AlN nanocones and CsI-AlN-6 nanostructures. (c) SEM images of CsI-AlN-6 nanostructures. This area corresponds to the EDS spectrum of CsI-AlN-6 in (b).

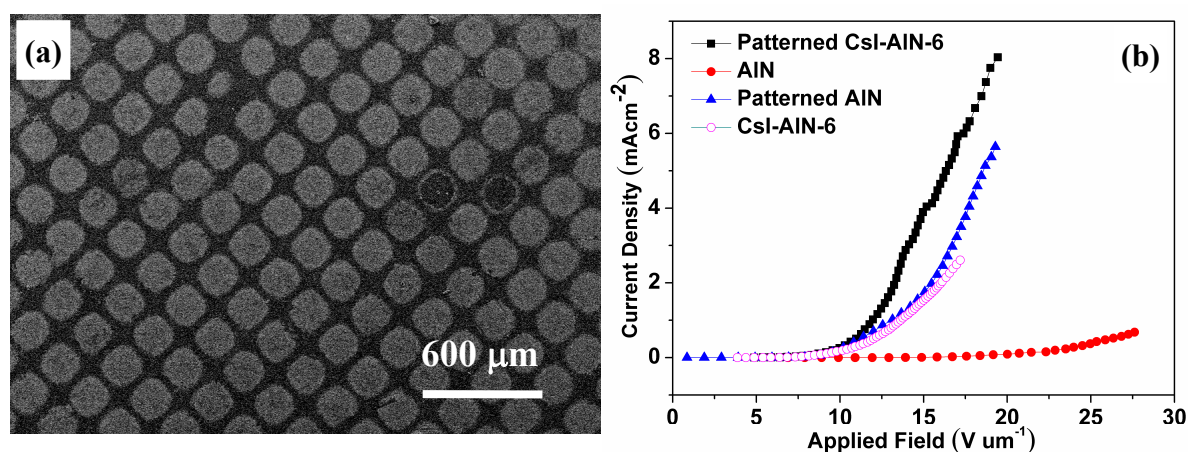
It is seen that the pristine nanocones is composed of hexagonal AlN with the preferential growth direction of [001]. EDS spectrum shows the signals of Al and N from AlN, as well as Si signal from the substrate and Cl from surface adsorption. For CsI-AlN-6, many nanoparticles are attached on the surface of the AlN nanocones. The corresponding XRD and EDS results reveal that the nanoparticles are CsI.

### SI-3. (HR)TEM characterization on the CsI-AIN-8 sample



**Fig. S3** TEM (a-b) and HRTEM (c-d) images of the CsI-AIN-8 sample. Note: the images in (b) and (d) correspond to the nanostructures after ~30 s (HR)TEM observation. It is seen the CsI nanoparticles were tightly adhered on the surface of the AlN nanocones, which would be evaporated due to the high energy electron beam irradiation.

SI-4.  $E_{to}$  and  $E_{thr}$  of the patterned and unpatterned CsI-AlN-6 nanostructures



**Fig. S4** SEM image (a) and J-E curves (b) of the patterned CsI-AlN-6 nanostructure. Note: the J-E curves of the pristine AlN, patterned AlN, and CsI-AlN-6 samples are also shown in (b) for comparison.

**Table S1.**  $E_{to}$  and  $E_{thr}$  of the patterned and unpatterned CsI-AlN-6 nanostructure

Sample	$E_{to}$ ( $V \mu m^{-1}$ )	$E_{thr}$ ( $V \mu m^{-1}$ )	Note
AlN nanocones	15.2	>30	this work
Patterned AlN nanocones	7.7	13.1	Ref. 3 of this paper
CsI-AlN-6	7.0	13.6	this work
Patterned CsI-AlN-6	6.6	11.8	this work*

\*The field emission property of the patterned CsI-AlN-6 nanostructure is better than the unpatterned one due to the decreased screening effect.

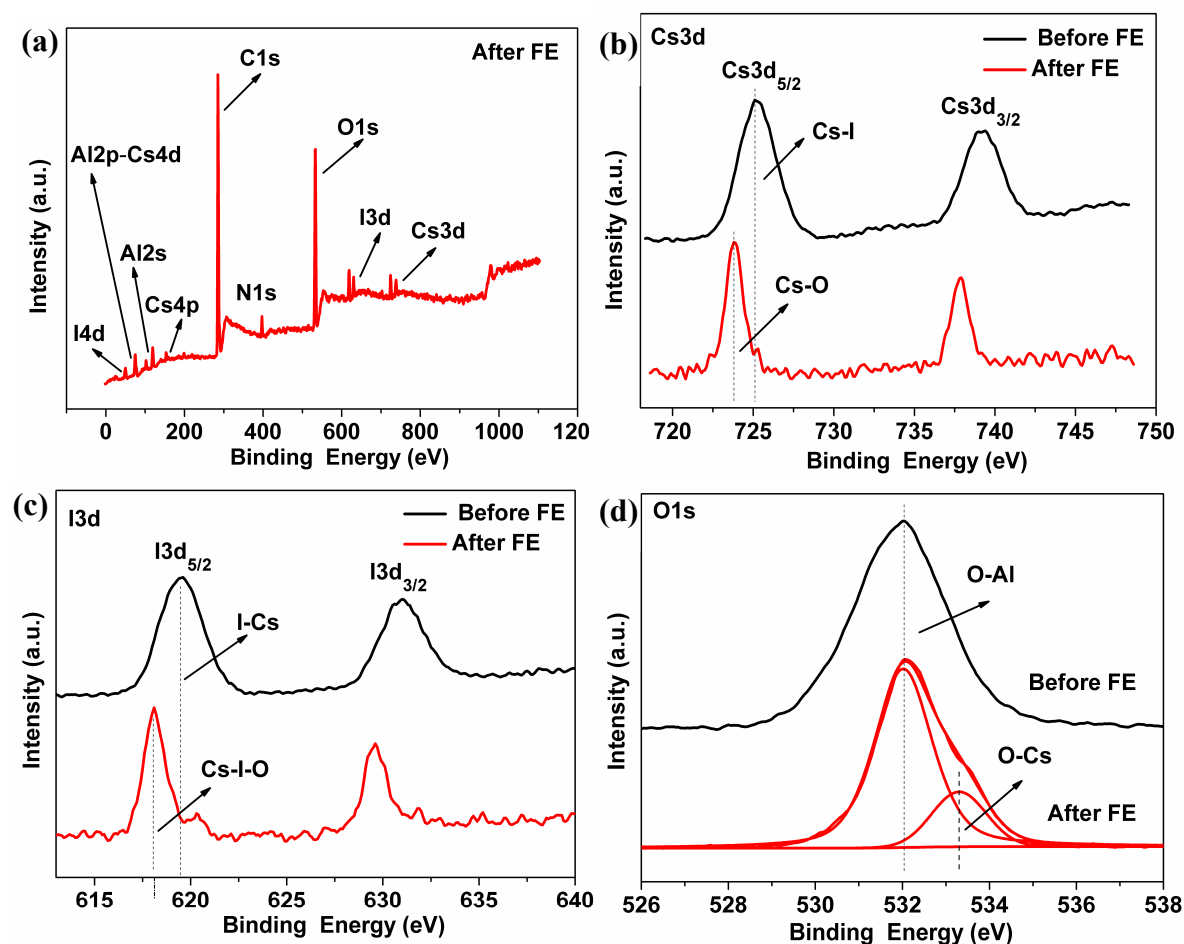
SI-5. Comparison of  $E_{to}$  and  $E_{thr}$  between CsI-AlN-6 and some other nanostructures

**Table S2.**  $E_{to}$  and  $E_{thr}$  of some nanostructures

Sample	$E_{to}$ ( $V \mu m^{-1}$ )	$E_{thr}$ ( $V \mu m^{-1}$ )	Note
WO <sub>3</sub>	1.8	3.3	Ref. 31 of this paper
CdS	3.7	9.3	Ref. 32 of this paper
ZnS	3.69	/	Ref. 33 of this paper
Patterned AlN nanocones	4.8/7.7	11.2/13.1	Ref. 3 of this paper
Si-doped AlN	1.8	4.6 at $10 \text{ mA cm}^{-2}$	Ref. 17 of this paper
CsI-AlN-6	7.0	13.6	this work

$E_{to}$  and  $E_{thr}$  correspond to the electric field to generate an emission current density of  $10 \mu A \text{ cm}^{-2}$  and  $1 \text{ mA cm}^{-2}$ , respectively.

SI-6. XPS spectra of the hybrid samples before and after field emission measurement



**Fig. S5** XPS spectra of the CsI-AlN-6 hybrid samples before and after field emission (FE) measurement. (a) survey; (b) Cs3d; (c) I3d; (d) O1s.

Note: The binding energies for the marked species are about 723.8 and 725.1 eV for Cs-O<sup>1</sup> and Cs-I in (b), 619.5 and 618.2 eV for I-Cs and Cs-I-O<sup>2,3</sup> in (c), 532.0 and 533.3 eV for O-Al and O-Cs in (d). It is noticed that both Cs3d and I3d signals shift to the low binding energy side for about 1.3 eV after FE.

**Reference**

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